



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of: Robert J. SMALL

Confirmation No. 4672

Application No.: 10/802,780

Art Unit: 1746

Filed: March 18, 2004

Examiner: Michael A. Marcheschi

For: **RESIDUE REMOVERS FOR
ELECTROHYDRODYNAMIC
CLEANING OF SEMICONDUCTORS**

Atty Docket No.: 060937-0178-US

INFORMATION DISCLOSURE STATEMENT

U.S. Patent and Trademark Office
2011 South Clark Place, Customer Window
Mail Stop AMENDMENT
Crystal Plaza Two, Lobby, room 1B03
Arlington, Virginia 22202

Sir:

In accordance with the duty of disclosure provisions of 37 C.F.R. §1.56, there is hereby provided certain information which the Examiner may consider material to the examination of the subject U.S. patent application. It is requested that the Examiner make this information of record if it is deemed material to the examination of the application.

Enclosed with this Information Disclosure Statement is a list of all patents, publications, applications, or other information submitted for consideration by the Office. These references are noted in the application. There are thirty (30) references listed in the above-referenced application; no U.S. references are submitted, however, the two (2) articles are submitted herewith. Remaining references can be provided upon request.

A fee of \$180.00 is believed to be due for this submission, since this Information Disclosure Statement is being submitted after an Office Action, but before the final Office Action. Should any fees be required, however, please charge the required fees to Morgan, Lewis & Bockius LLP Deposit Account No. 50-0310.

Respectfully submitted,

By:

September 23, 2004


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09/24/2004 EFLORES 00000141 500310 10802780
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<p style="text-align: center;">LIST OF REFERENCES CITED BY APPLICANT <small>(Use several sheets if necessary)</small></p> <p style="text-align: center;">P E C SEP 23 2004 PATENT & TRADEMARK OFFICE</p>	ATTY DOCKET NO.	APPLICATION NO
	060937-0179	10/361,822
	APPLICANT	
	Brandon Shane SCOTT et al.	
FILING DATE	GROUP	
February 11, 2003	1755	

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
A01	3,293,093	12/1966	Jones et al.			
A02	4,769,073	09/1988	Tastu et al.			
A03	4,959,113	07/1989	Roberts			
A04	5,527,423	06/1996	Neville et al.			
A05	5,354,490	09/1994	Finnigan			
A06	5,445,996	08/1995	Kodera et al.			
A07	5,773,364	06/1998	Farkas et al.			
A08	5,783,489	07/1998	Kaufman et al.			
A09	5,958,288	09/1999	Mueller et al.			
A10	5,891,205	04/1999	Picardi et al.			
A11	6,117,026	09/2000	Hayashi et al.			
A12	6,117,783	09/2000	Small et al.			
A13	6,156,661	12/2000	Small et al.			
A14	6,235,693	05/2001	Cheng et al.			
A15	6,248,704	06/2001	Cheng et al.			
A16	6,251,150	06/2001	Small et al.			
A17	6,313,039	11/2001	Small et al.			
A18	6,435,947	08/2002	Mueller et al.			
A19	6,498,131	12/2002	Small et al.			
A20						
A21						

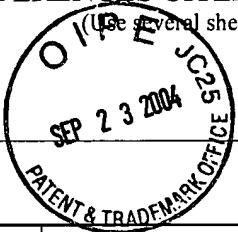
FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES NO
B01						
B02						

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

C01	"Mechanistic Aspects of Chemical mechanical Polishing of tungsten Using Ferric Ion Based Alumina Slurries" by Raghunath et al., ESP, Vol. 96-22, pp. 1-15
C02	"Electrochemical Aspects of the Chemical Mechanical Planarization of Tungsten" by Basak et al., ESP Vol. 96-22, pp. 137-148

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*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
A01	6,022,400	2/2000	Izumi et al.			
A02	6,177,026	1/2001	Wang et al.			
A03	6,251,150	6/2001	Small et al.			
A04	6,435,947	08/2002	Mueller et al.			
A05	5,302,356	04/1994	Shadman et al.			
A06	6,468,428	10/2002	Nishii et al.			
A07	6,461,227	10/2002	Fang			
A08	6,375,545	04/2002	Yano et al.			
A09	2002/0017063	02/2002	Beitel et al.			

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B01								
B02								
B03								
B04								
B05								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

C01	
C02	
C03	

EXAMINER	DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.